

N-Channel Logic Level Enhancement Mode Field Effect Transistor

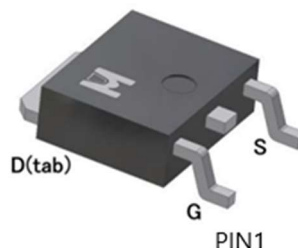
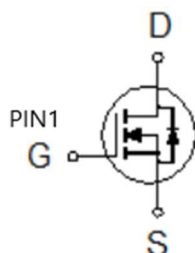
Product Summary:

BV_{DSS}	100V
$R_{DS(on)} (MAX.)$	25m Ω
I_D	35A

N Channel MOSFET

UIS, Rg 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS ($T_c = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 30	V
Continuous Drain Current	$T_c = 25^\circ\text{C}$	I_D	35	A
	$T_c = 100^\circ\text{C}$		22	
Pulsed Drain Current ¹		I_{DM}	140	
Avalanche Current		I_{AS}	50	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	125	mJ
Repetitive Avalanche Energy ²	$L = 0.05\text{mH}$	E_{AR}	62.5	
Power Dissipation	$T_c = 25^\circ\text{C}$	P_D	50	W
	$T_c = 100^\circ\text{C}$		20	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	$^\circ\text{C}$

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$		2.5	$^\circ\text{C} / \text{W}$
Junction-to-Ambient	$R_{\theta JA}$		50	

¹Pulse width limited by maximum junction temperature.

²Duty cycle $\leq 1\%$

ELECTRICAL CHARACTERISTICS ($T_c = 25\text{ }^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	100			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	3.0	4.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 30V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 80V, V_{GS} = 0V$			1	μA
		$V_{DS} = 70V, V_{GS} = 0V, T_J = 125\text{ }^{\circ}C$			25	
On-State Drain Current ¹	$I_{D(ON)}$	$V_{DS} = 10V, V_{GS} = 10V$	35			A
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 30A$		21.5	25	mΩ
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 30A$		38		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 50V, f = 1MHz$		1575		pF
Output Capacitance	C_{oss}			216		
Reverse Transfer Capacitance	C_{rss}			47		
Gate Resistance	R_g	$V_{GS} = 15mV, V_{DS} = 0V, f = 1MHz$		1.5		Ω
Total Gate Charge ^{1,2}	Q_g	$V_{DS} = 80V, V_{GS} = 10V, I_D = 30A$		20.8		nC
Gate-Source Charge ^{1,2}	Q_{gs}			8.5		
Gate-Drain Charge ^{1,2}	Q_{gd}			6.8		
Turn-On Delay Time ^{1,2}	$t_{d(on)}$	$V_{DS} = 50V, I_D = 1A, V_{GS} = 10V, R_{GS} = 6\Omega$		20		nS
Rise Time ^{1,2}	t_r			80		
Turn-Off Delay Time ^{1,2}	$t_{d(off)}$			90		
Fall Time ^{1,2}	t_f			100		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T _C = 25 °C)						
Continuous Current	I_S				35	A
Pulsed Current ³	I_{SM}				140	
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 25A, dI_F/dt = 100A / \mu S$		120		nS
Reverse Recovery Charge	Q_{rr}			380		nC

¹Pulse test : Pulse Width $\leq 300\text{ }\mu\text{sec}$, Duty Cycle $\leq 2\%$.

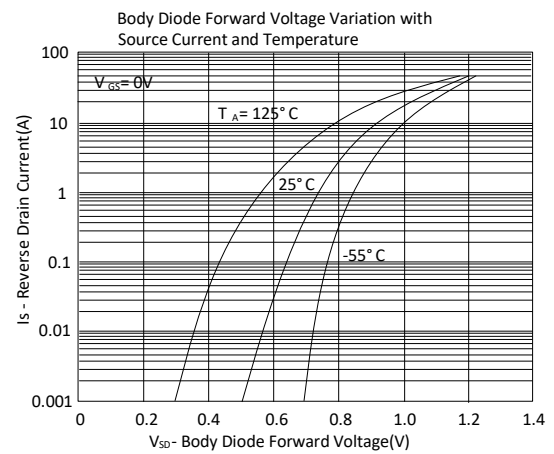
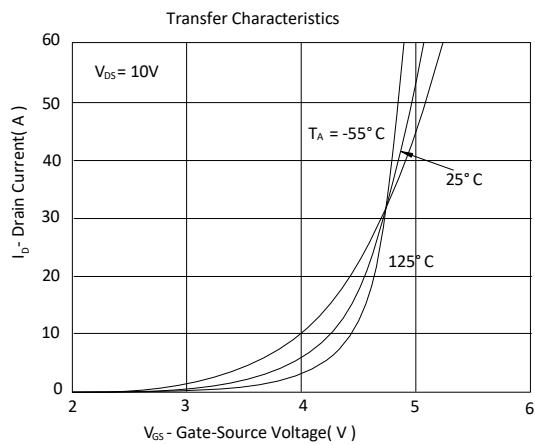
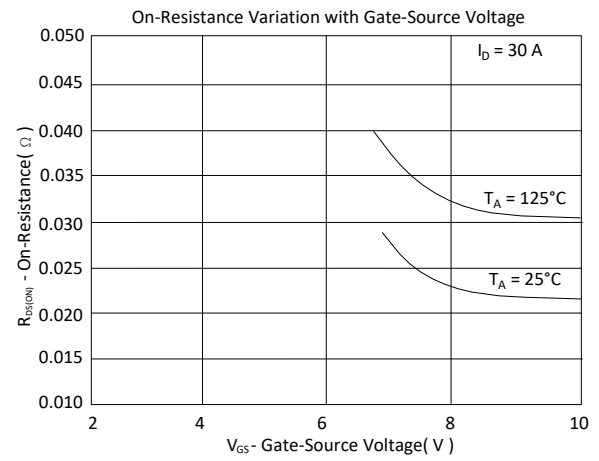
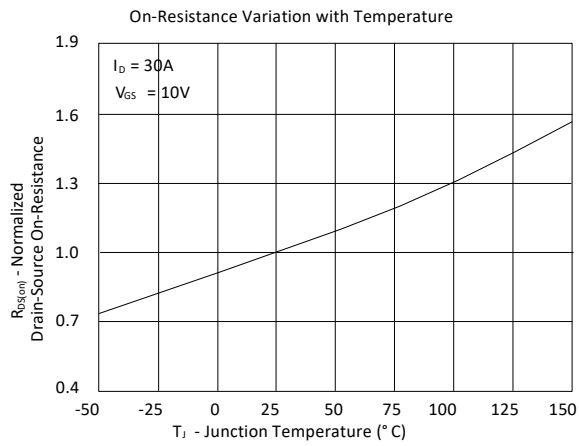
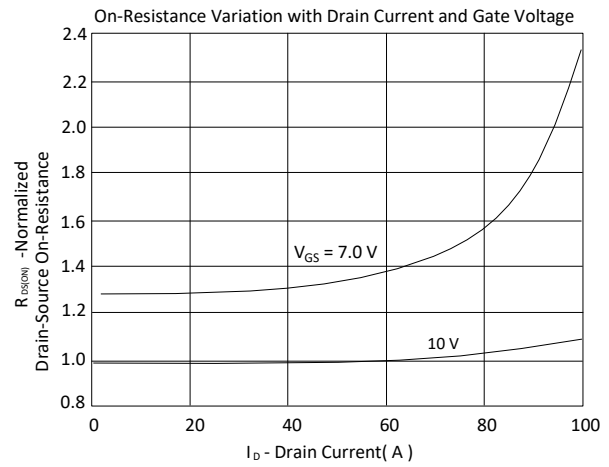
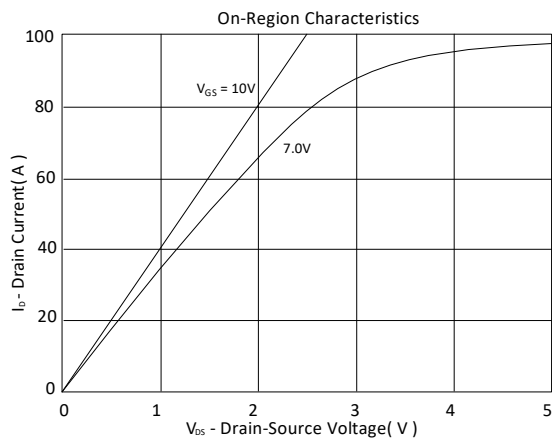
²Independent of operating temperature.

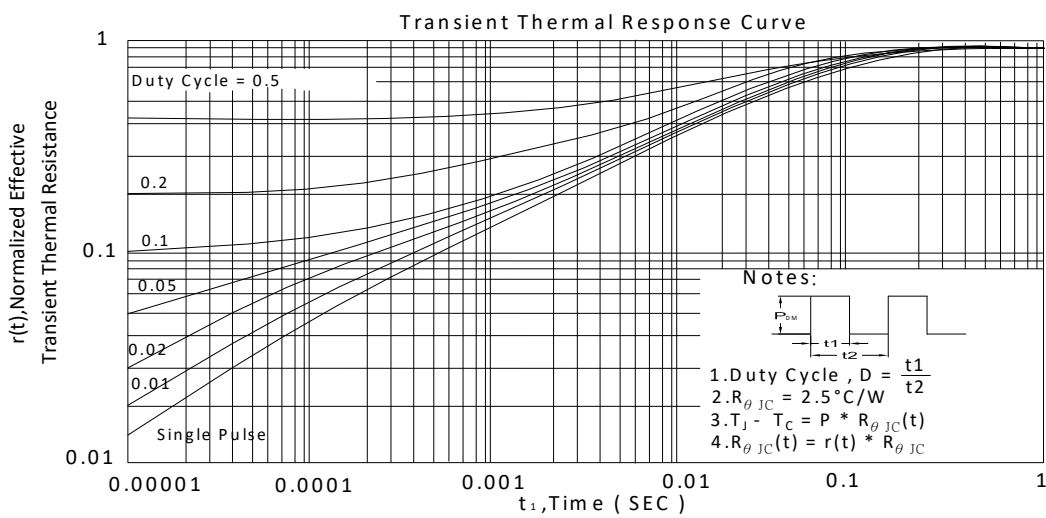
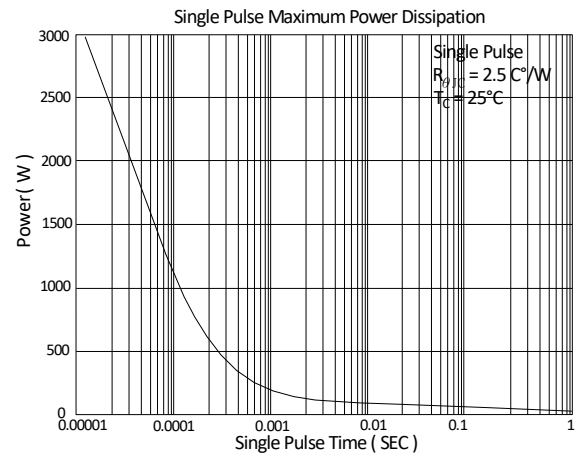
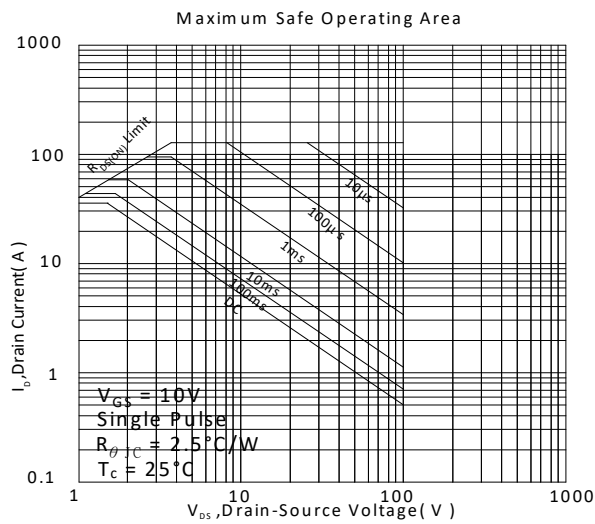
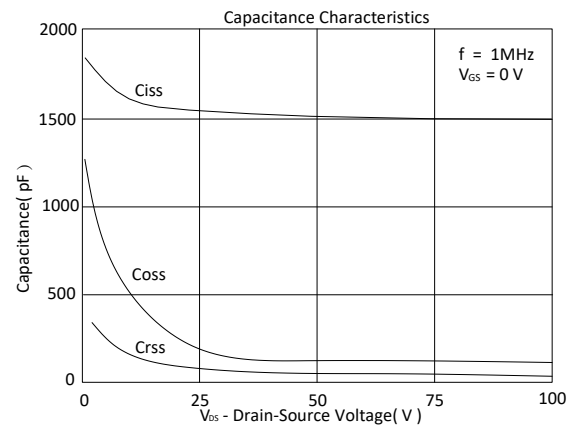
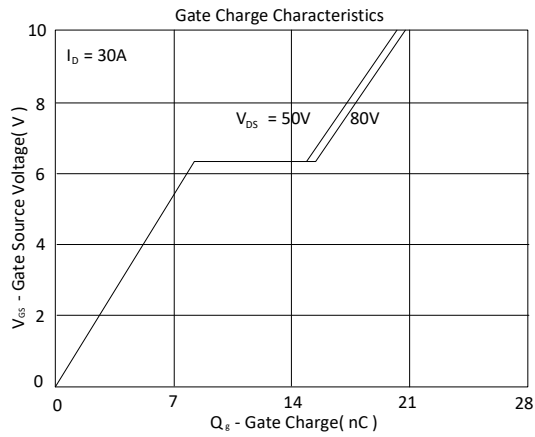
³Pulse width limited by maximum junction temperature.

EMC will review datasheet by quarter, and update new version.



TYPICAL CHARACTERISTICS





Ordering & Marking Information:

Device Name: EMD25N10A for DPAK (TO-252)



EMD25N10A : Device Name

ABCDEFGH: Date Code

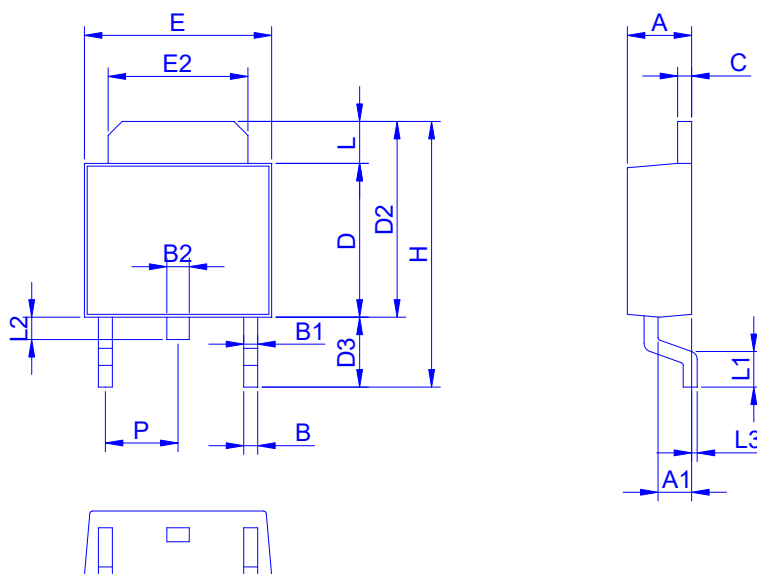
A: Assembly House

B: Year(A:2008 B:2009 C:2010....)

C: Month(A:01 B:02 C:03 D:04 E:05 F:06 G:07 H:08 I:09 J:10 K:11 L:12)

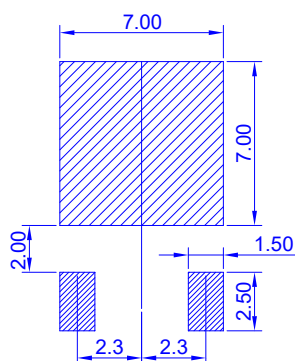
DEFG: Serial No.

Outline Drawing

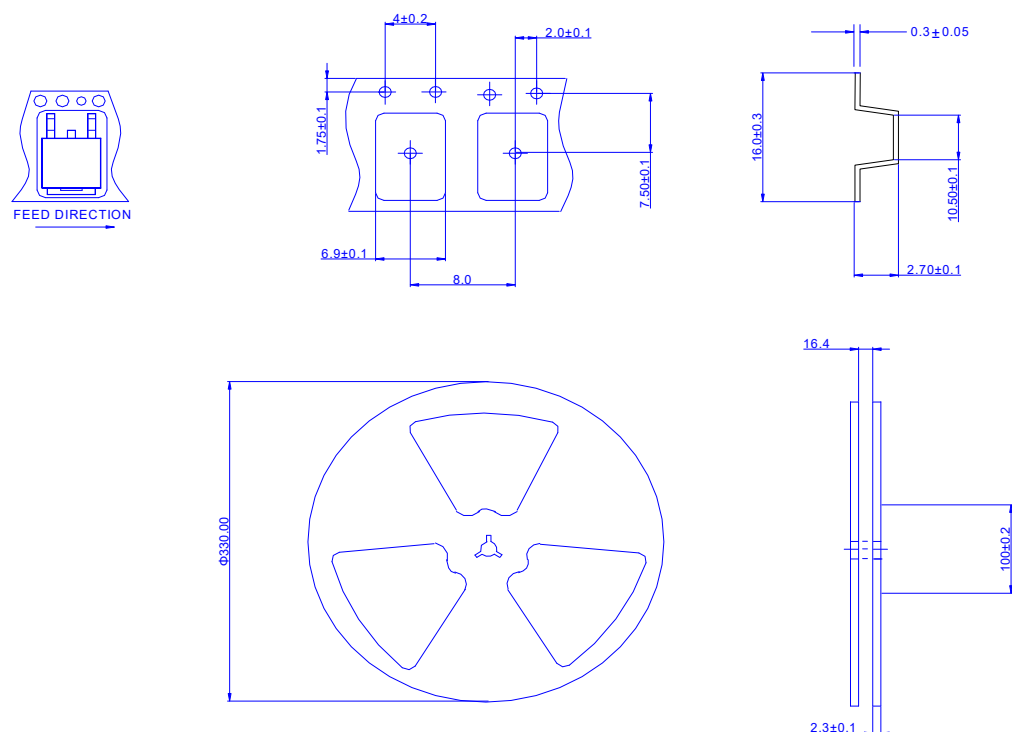


Dimension	A	A1	B	B1	B2	C	D	D2	D3	E	E2	H	L	L1	L2	L3	P
Min.	2.10	0.95	0.30	0.40	0.60	0.40	5.30	6.70	2.20	6.40	4.80	9.20	0.89	0.90	0.50	0.00	2.10
Max.	2.50	1.30	0.85	0.94	1.00	0.60	6.20	7.30	3.00	6.70	5.45	10.15	1.70	1.65	1.10	0.30	2.50

Footprint



◆ Tape&Reel Information:2500pcs/Reel(Dimension in millimeter)



產品別	TO252-2
Reel 尺寸	13"
編帶方式	FEED DIRECTION 
前空格	35
後空格	35
裝箱數	
滿捲數量	2.5K
捲/內盒比	1 : 1
內盒滿箱數	2.5K
內/外箱比	10 : 1
外箱滿箱數	25K